

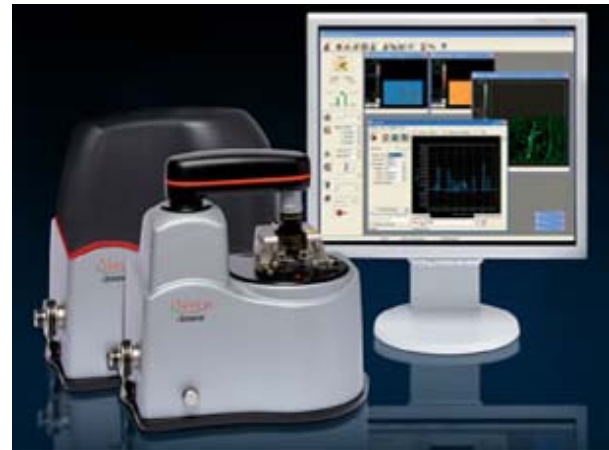


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Your first choice to product development, quality assurance and IP strategy!!!

## Conductive-AFM (INNOVA)

### Applications :

- A. It can be used in failure analysis of leakage or higher resistance contact, junction leakage, gate oxide leakage and etc.
- B. To discriminate various contact types (P+/N+/Poly CT).
- C. To diagnose the failure mechanism by comparing I/V curves of different contact types.
- D. To provide I-V information of specific point.



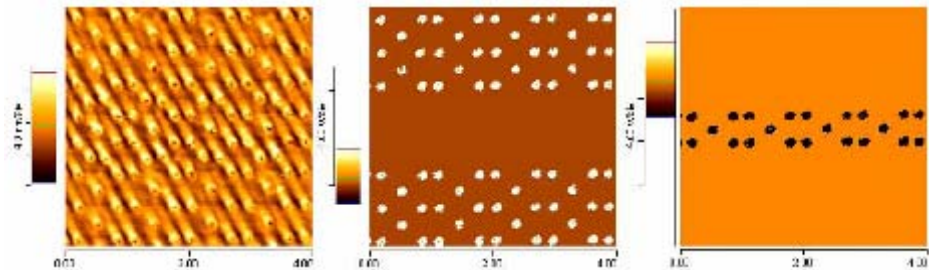
Conductive-Atomic Force Microscope (INNOVA C-AFM)

Topography

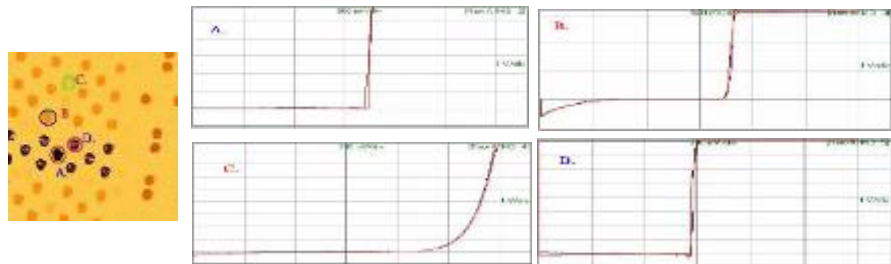
Current with +1V bias

Current with -1V bias

CAFM gets topography by contact Mode and gets current signal simultaneously.



We can see totally different properties among these 4 points (A, B, C, D).



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You are highly welcome to use Fedex (account no. 2665-9953-6) , DHL (account no. 968368648) or UPS services for sample shipping. ma-tek pay the courier charge upon sample arrival.



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